

No amendments have been made to the claims, and the claims are listed merely for reference:

**Amendments to the Claims:**

5 This listing of claims will replace all prior versions and listings of claims in the application:

**Listing of Claims:**

1. (currently amended) A method of defect review comprising following steps:  
providing a wafer with a plurality of defects;  
performing a defect inspection to detect the defects;  
10 performing an automatic defect classification according to a database to separate the defects into a plurality of defect types;  
adjusting sampling ratios according to an influence degree each defect type has on process yield; and  
performing a defect review using the adjusted sampling ratios. ;  
15 ~~wherein each defect type has different sampling ratios in the defect review according to its influence degree of process yield.~~
  2. (original) The method of claim 1 wherein the database comprises information about the plurality of defect types and defect information corresponding to each defect  
20 type.
  3. (original) The method of claim 2 wherein the defect information comprises the influence degree of the process yield of each defect type.
  - 25 4. (original) The method of claim 3 wherein the database separates the defect types into killer defects and non-killer defects according to the influence degree of the process yield.
  5. (original) The method of claim 4 wherein the sampling ratio of the killer defects  
30 in the defect review is larger than that of the non-killer defects.
  6. (original) The method of claim 3 wherein the database separates the defects into

pre-layer defects and adding defects, and further separates the adding defects into killer defects and non-killer defects.

7. (original) The method of claim 6 wherein the defect review focuses on the  
5 adding defects.

8. (original) The method of claim 1 wherein after finishing the defect inspection, a judgment of cluster defects is performed and a defect review with a high sampling ratio is performed on the cluster defects if the cluster defects exist.  
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9. (original) The method of claim 1 wherein the database is updated according to the result of the defect review after finishing the defect review.